

Lecture – Southern California Chapter of the American Vacuum Society Thin Film Filters and **Coatings for UV** Astronomy, Astrophysics, and Planetary Science

Presented by: Dr. April D. Jewell



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July 21, 2020

Jet Propulsion Laboratory California Institute of Technology

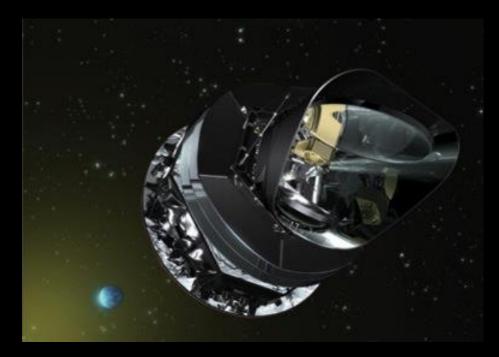
Jet Propulsion Laboratory

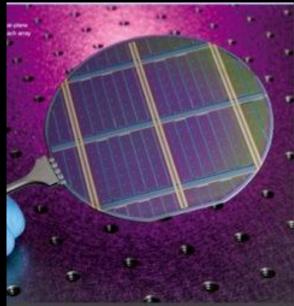
- Founded in 1936 as a graduate student project under Prof. Von Karman (Caltech)
- Transferred to NASA upon its creation in 1958
- JPL is a Federally Funded Research and Development Center (FFRDC) under NASA Sponsorship
- A division of Caltech, staffed with >5000 Caltech employees; JPL Director is a Vice-President of Caltech
- Programs
 - NASA
 - Defense programs and civilian programs of national importance compatible with JPL capabilities



NASA/JPL Mission Concept and Technology Development

- Start from broad questions asked by NASA Roadmaps
 - Is there life on other planets?
 - How did the universe form?
- Missions are formulated to address these questions
 - Mars Science Laboratory (MSL) Curiosity
 - Goal: Examine the habitability of Mars
 - Hubble Space Telescope/Kepler/GALEX
 - Goal: Understand how stars, planets, galaxies, and the universe formed





Microdevices Laboratory (MDL)

- MDL invents and develops a broad spectrum of unique flight-worthy micro-devices that enable a wide variety of instruments and missions across the full range of JPL's activities in earth science, planetary exploration, and astrophysics and cosmology
- Core Competencies include:
 - UV-Visible Detectors + Systems
 - Mid-IR Detectors ullet
 - Sub-mm Devices ullet
 - Superconducting Devices
 - **Semiconductor Lasers** ullet
 - **Diffractive Optics**





https://microdevices.jpl.nasa.gov/



Advanced Detectors, Systems, and Nanoscience Overall Objective of Group/Team

Develop UV/Vis/NIR detectors, technologies, and systems focused on the needs of NASA (and NASA partners') missions and instruments



Balloons





CubeSats & SmallSats

New Frontiers and Discovery Missions

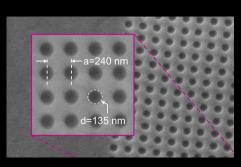


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Large Strategic Science Missions (Flagships)

Develop detectors and systems to stay at the cutting edge and in response to non-NASA sponsors and to national needs

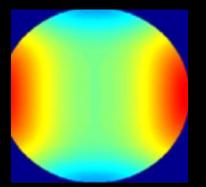


Metamaterials



Medical & Diagnostic Imaging

Semiconductor Fab/Wafer Inspection





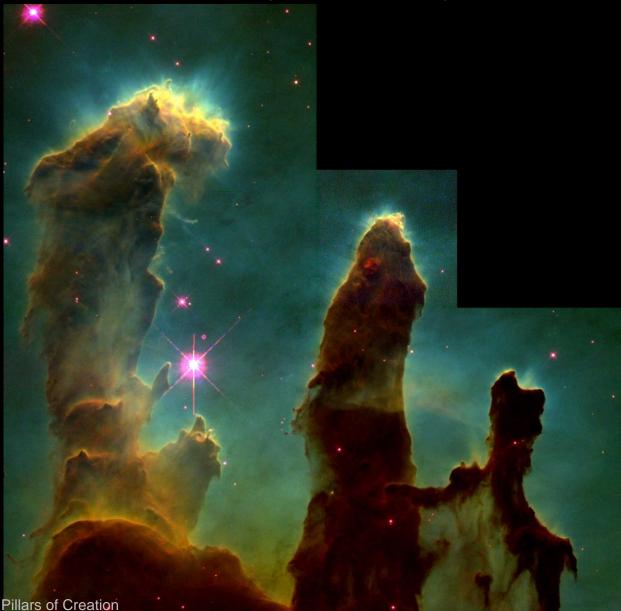
Sandia's Z-Machine

High Energy Physics jpl.nasa.gov

Silicon Detectors for Astronomy, Astrophysics & Planetary Science

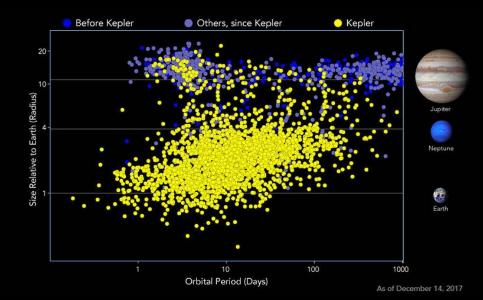
Hubble Space Telescope

Cassini

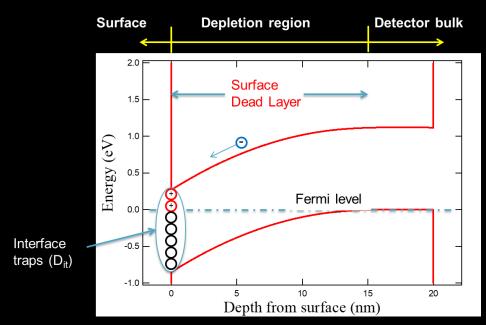




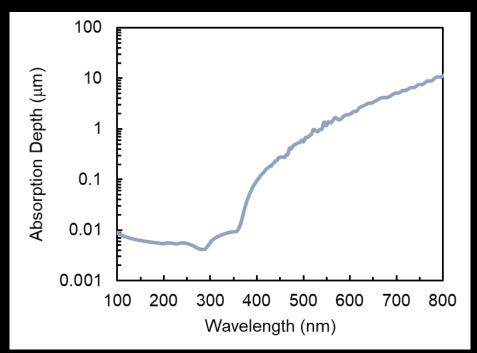
Kepler Space Telescope

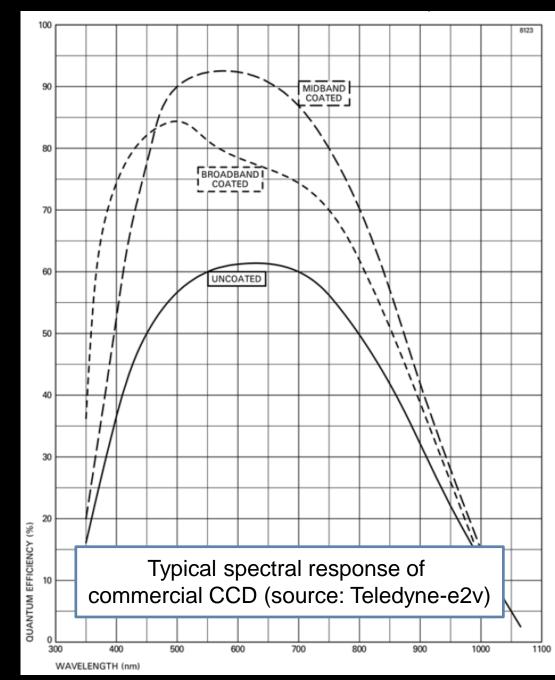


The Surface/Interface Problem – Dead Layer



Hoenk et al., APL, 61 (1992) 1084

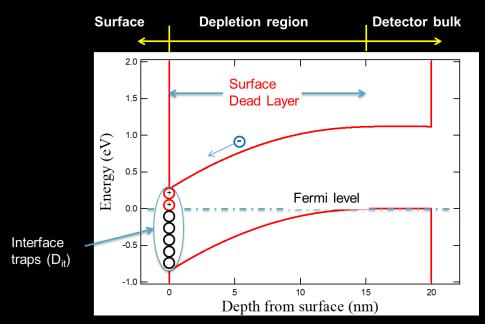




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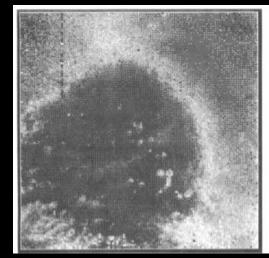


The Surface/Interface Problem – Dead Layer

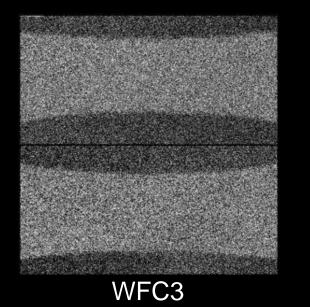


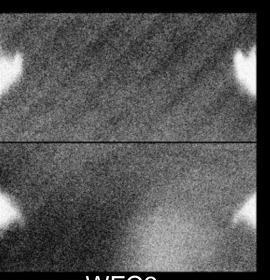
Hoenk et al., APL, 61 (1992) 1084

Surface Charging; QE Hysteresis



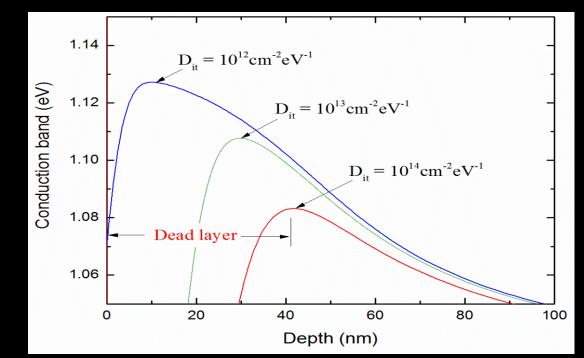
WF/PC 1





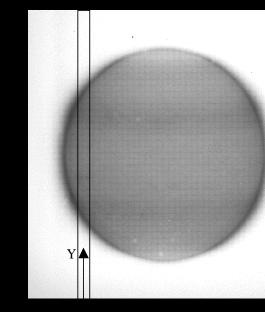
WFC3 Wong, Inst. Sci. Rep. WFC3, 2009-07

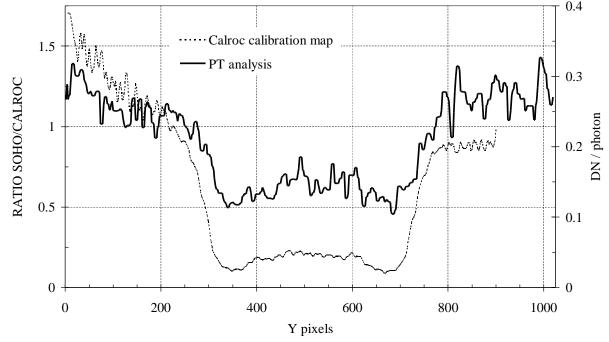
Surface/Interface Damage



Hoenk et al., Proc. SPIE, 9154 (2014) 13

ESA's Solar & Heliospheric Observatory (SOHO) **Extreme UV Imaging Telescope (EIT)**

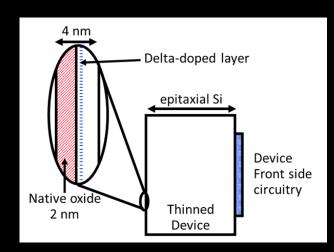


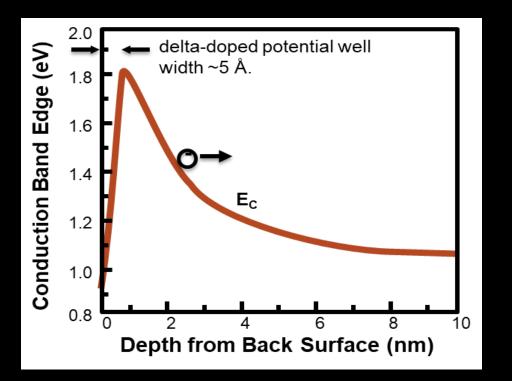


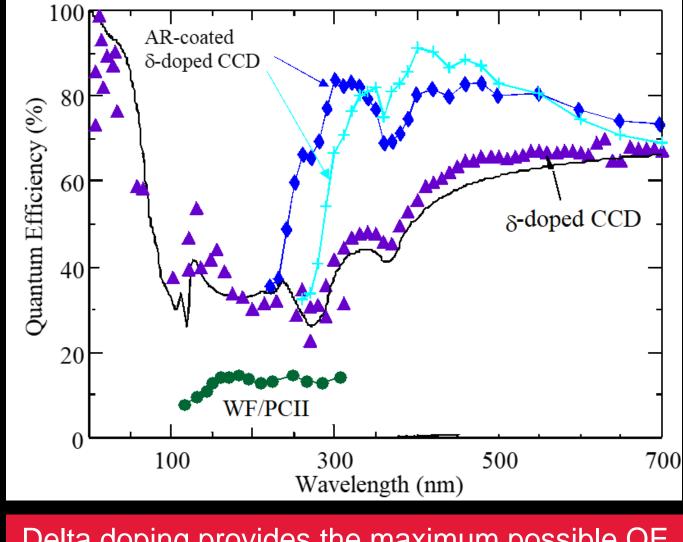
jpl.nasa.gov

Defise et al., Proc. SPIE 3442 (1998) 126 Moses et al., Solar Physics 175 (1997) 571

Passivation by Two-dimensional Delta Doping





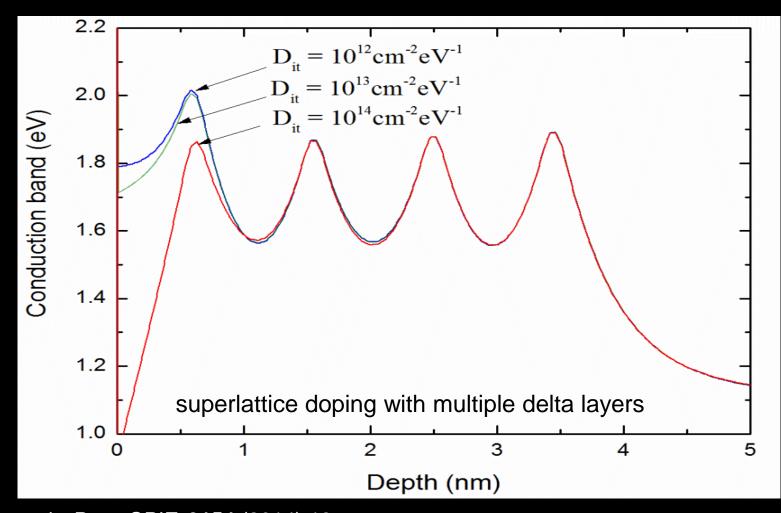


Delta doping provides the maximum possible QE

Hoenk et al., APL, 61 (1992) 1084 Nikzad et al., Proc. SPIE 4139 (2000) 250

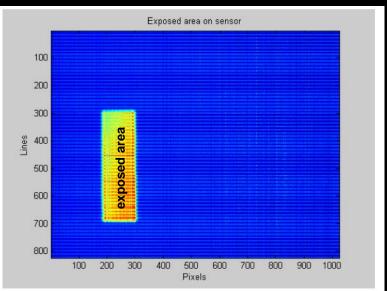


Stability of 2D-doped Surface

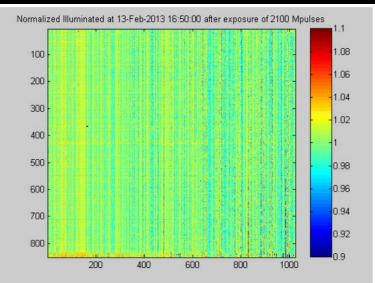


Hoenk et al., *Proc. SPIE*, **9154** (2014) 13

Superlattice-doped CMOS Detector



Normalized Illuminated Image



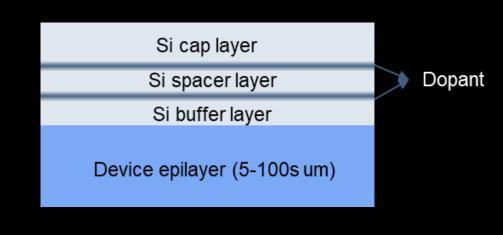
No change in response after 2.1 Billion saturating pulses in the deep UV

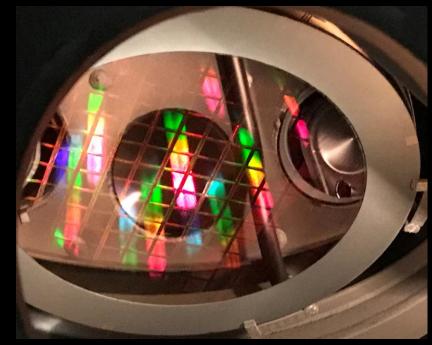


Growth Structure/Process

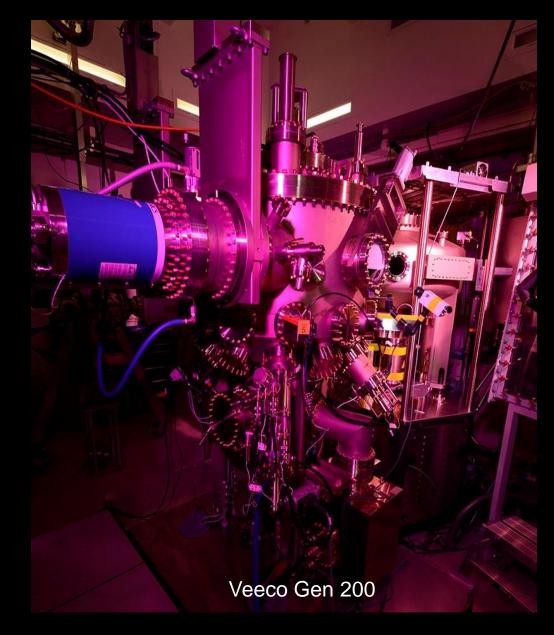
Low Temperature MBE

- Performing passivation as a post-fabrication step
- T≤450 °C
- Silicon deposited by e-beam evaporation (<0.5 Å/s)
- P-type doping with B from effusion cell
- N-type doping with Sb from cracker cell
- Deposited silicon layers typically 1-3 nm
- Dopant concentration <1 monolayer (where 1 ML ~ 7E14 cm⁻²)
 - Typical 1E14 or 2E14

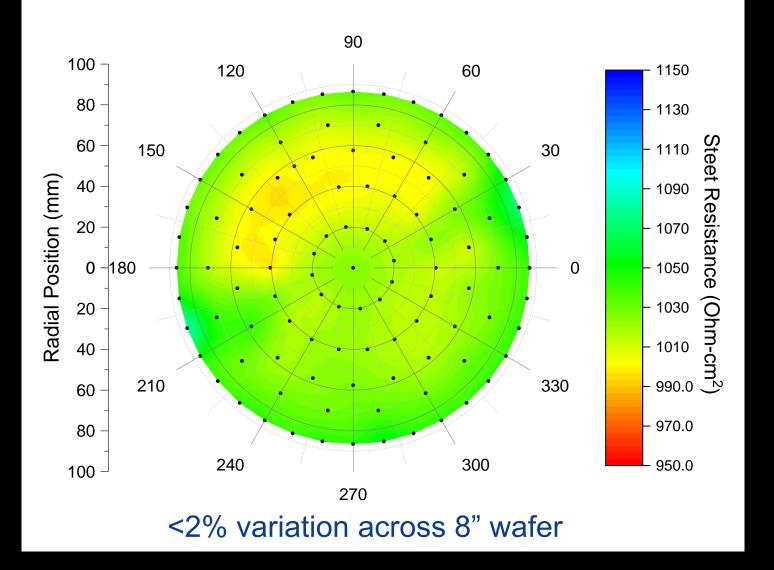


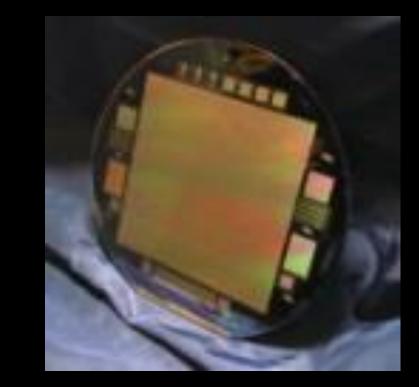


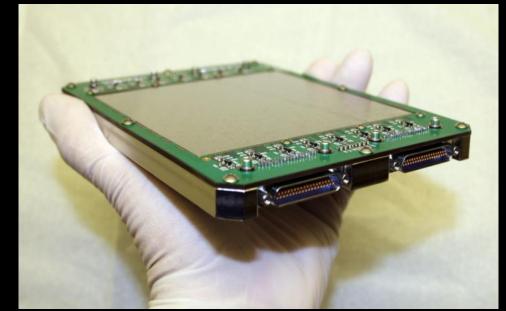




Wafer-scale Processing







Images Courtesy: Semiconductor Technology Associates, Inc.

Jewell et al., JVSTA, 936 (2018) 061513

Tailoring Detector Response with Thin Film Filters and Coatings

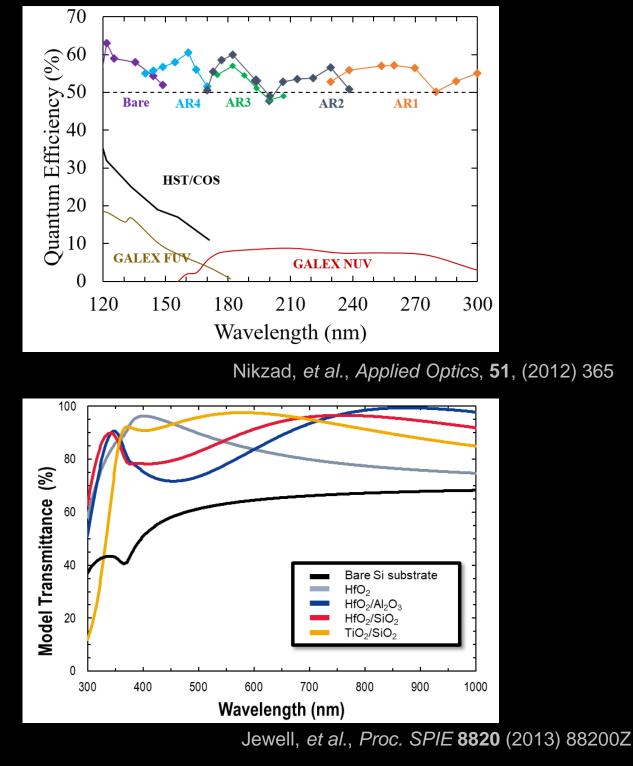


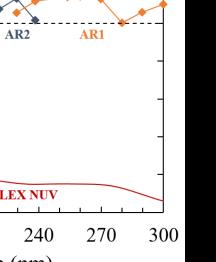
Antireflection Coatings

Single and Multilayer Films

Specified wavelengths or bands for targeted applications can be optimized depending on coating materials and overall design.

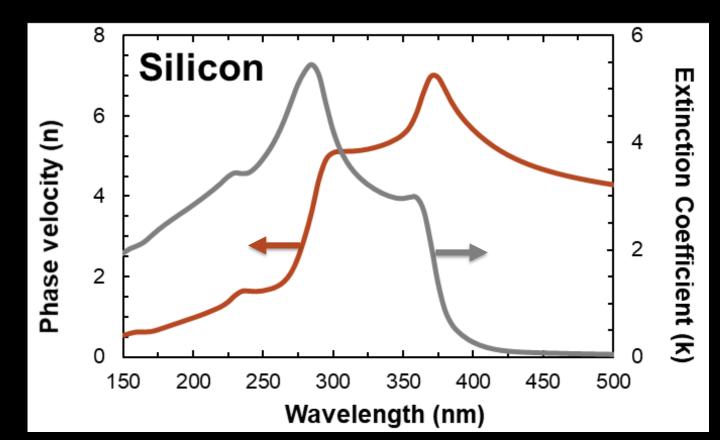






Antireflection Coatings

- Baseline response of our detectors is reflection limited (i.e. follows 1-R)
- AR coatings can be used to minimize reflection losses
- Index of refraction (n) of silicon changes significantly in the UV
- Maximum performance requires that AR coatings be used
 - Thin films (10-25 nm) required in UV
 - Intermediate thickness films (30-100 nm) for visible
- Specified wavelengths or bands for targeted applications can be optimized depending on coating materials and overall design



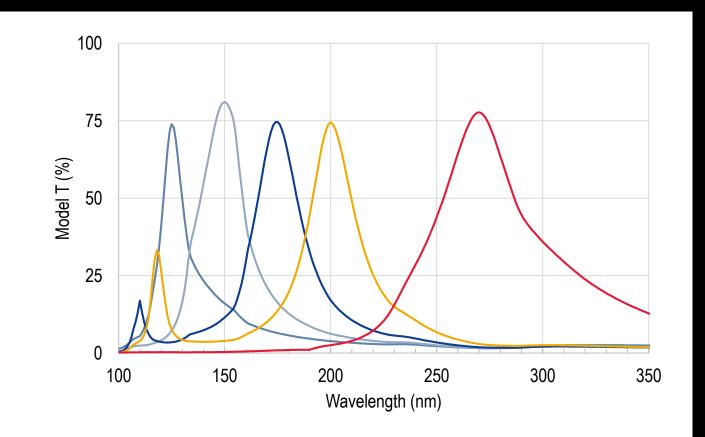
April Jewell, SCCAVS Lecture

Solar-Blind Silicon

2D-doped Detectors with Integrated Fabry-Pérot Filters

Metal-dielectric filter (MDF) stack deposited directly on silicon detector's substrate

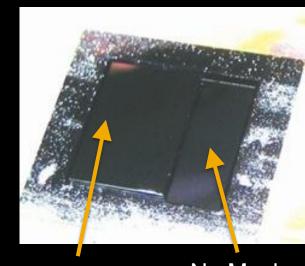
- Eliminate separate filter element
- Can match dielectric to bandpass
- Number of layers and thickness dictate in-band throughput and outof-band suppression



Sputtered, E-beam, and Thermal Evaporation

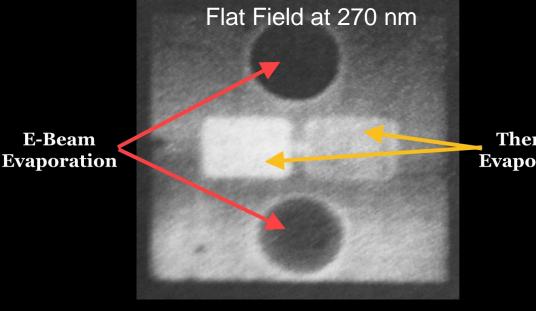
Case studies with HfO₂ (cutoff ~240 nm)

- Shadow mask used so that we have internal standard for comparison
- Flat field images and QE measurements
 - Brighter \rightarrow Higher QE
- Sputtered film: coated region showed lower QE at 300 nm. TEM showed low density, rough, amorphous film
- E-beam evaporation: also lower QE in coated region. Possible x-ray damage?
- Thermal evaporation: worked well, but challenges with uniformity and reproducibility

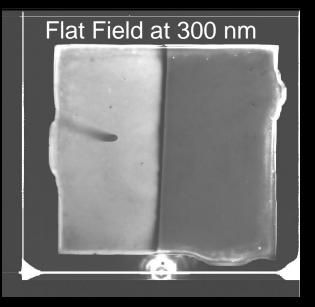


Shadow mask

No Mask



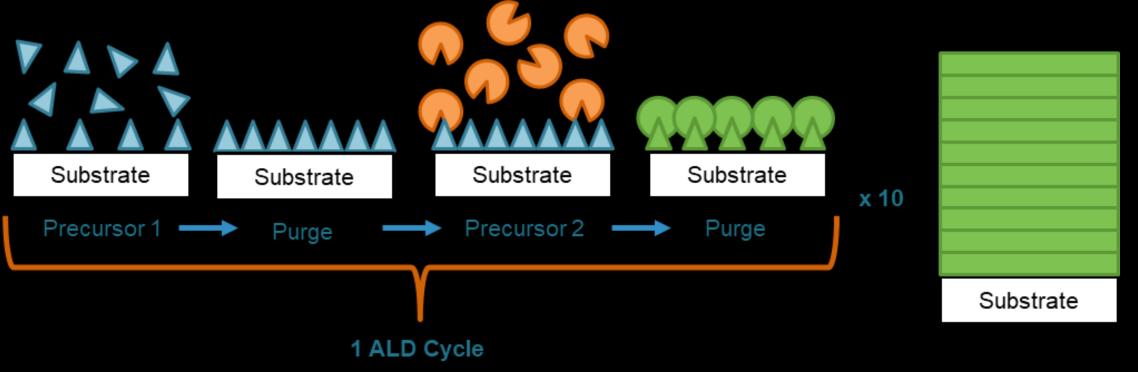
Sputtered Film



Thermal Evaporation

Atomic layer deposition

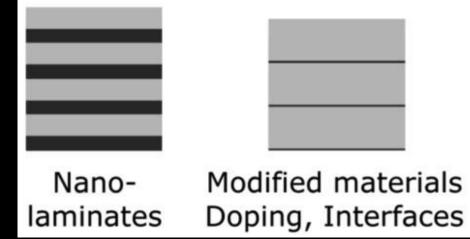
- Thin film deposition technique based on sequential, self-limiting chemical reactions.
- Chemical reactants (precursors) are introduced to the substrate in separate steps \bullet isolated by purges with a non-reactive gas (e.g., N₂, Ar, etc.)
- ALD growth is typically based on thermally driven reactions or plasma enhanced • reactions and can be used to grow conformal films with *nanometer-scale control* over film thickness, composition and structure, even at high aspect ratios

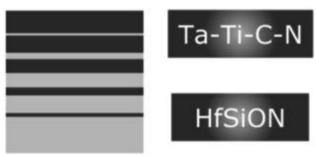


Growth rates measured in Å/cycle

ALD Materials (Old Slide!)

Oxides: Al₂O₃, HfO₂, SiO₂, TiO₂, ZnO, ZrO₂, MgO, SrTiO₃, HfSiO_x, HfAlO_x, LaAlO_x, Ta₂O₅, VO_x, Y₂O₃, CaO, CuO, Er₂O₃, Ga₂O₃, La₂O₃, Nb₂O₅, Sc₂O₃ etc. **Nitrides:** AIN, GaN, TaN, TiAIN, TiN, NbN etc. Carbides: TaC, TiC, NbC, etc. Metals: Ir, Pd, Pt, Ru, W, Mo, Cu, Ag, Au, etc. **Sulfides:** ZnS, SrS, CuS, FeS, MoS_x, etc. **Fluorides:** CaF₂, LaF₃, MgF₂, AIF₃, LiF, SrF₂, etc. **Biomaterials:** $Ca_{10}(PO_4)_6(OH)_2$ (hydroxyapatite) **Polymers:** PMDA-DAH, PMDA-ODA, etc.





Graded structures

Tailored mixtures

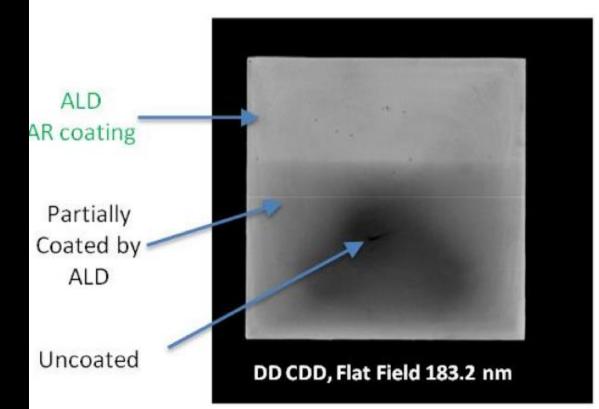
ALD for AR Coatings

Advantages of ALD

- Uniform, pinhole-free films ightarrow
- Dense, amorphous films \bullet
- Excellent thickness control
- Sharp interfaces
- Conformal coating to high aspect ightarrowratios (not a line of site technique)

Challenges with ALD

- Shadow masking does not work \bullet
- Patterning ALD films is an active field \bullet of study



ALD in JPL's Microdevices Lab

High-Throughput/Load Locked Beneq TFS-200



Five reactive metal precursors & H₂O Four thermal reactive sources for low vapor pressure precursors Reactive gases for thermal and plasma enhanced deposition (H_2, N_2, N_3) and O_2) T_{sample} 25-400 °C Configurable plasma source 200 mm wafer handling

ALD in JPL's Microdevices Lab

Four reactive metal precursors + H_2O Thermal gas precursors (NH₃, O₂) Plasma gases (O₂, H₂, N₂) 200 mm wafer handling T_{sample} setpoint 25 - 400 °C T_{precursor} setpoint up to 200 °C 300 W plasma power

Oxford OpAL ALD System



ALD – Uniformity and Repeatability

8" wafer before/after 3 layer AR coating



Test Wafer

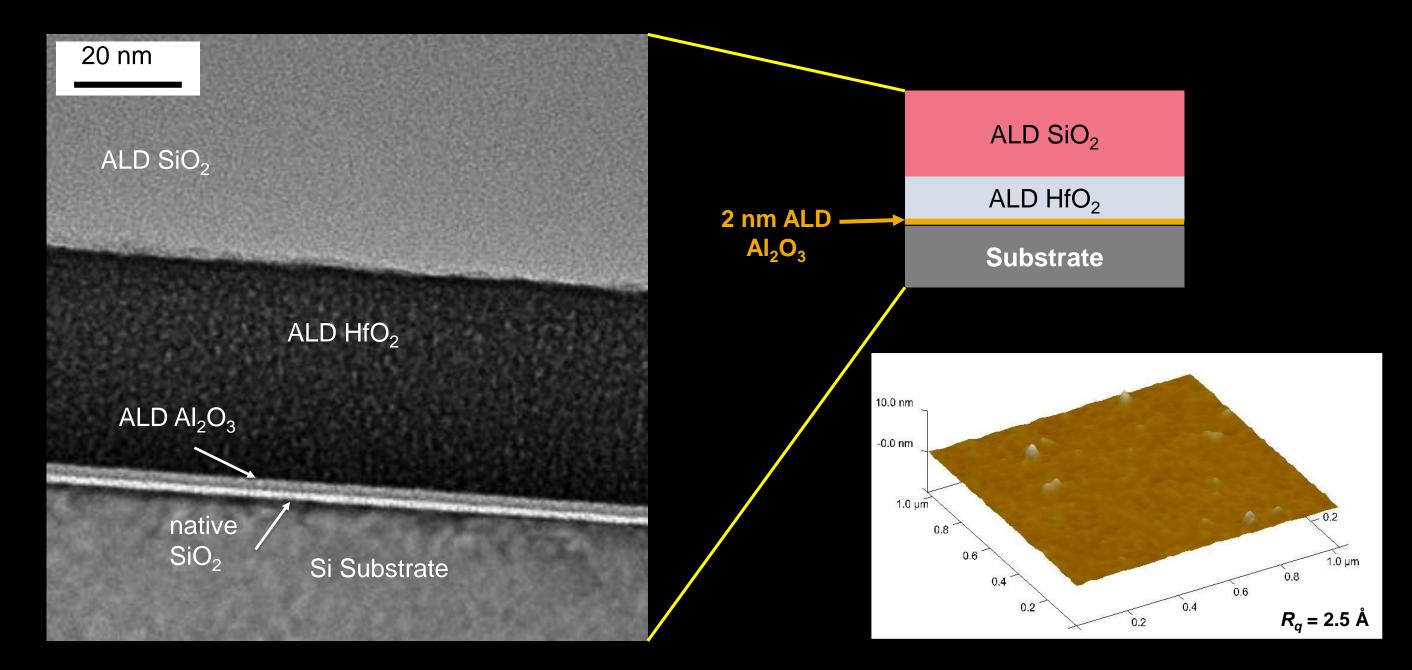




April Jewell, SCCAVS Lecture

Device Wafer

ALD – Surface Roughness & Interfaces

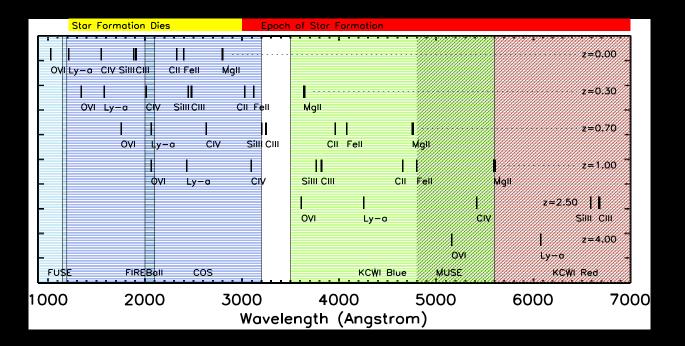


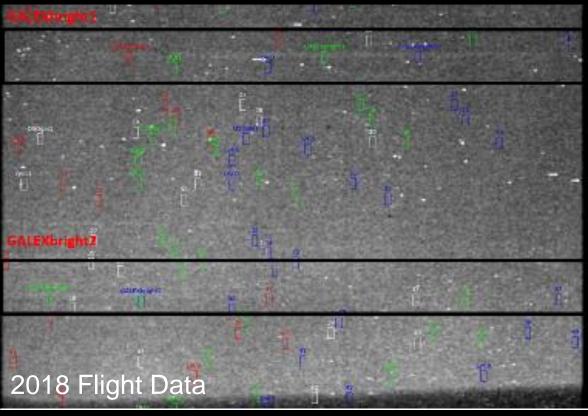
Recent and Ongoing Projects

Recent/Ongoing Suborbital Mission – FIREBall-2

Faint Intergalactic-medium Red-shifted Emission Balloon

- Discover and map faint emission from the ulletintergalactic medium of low redshift galaxies in the stratospheric UV window ~200-225 nm
- Delta-doped and AR coated detector
- Flight in 2018 complete; two more flights planned

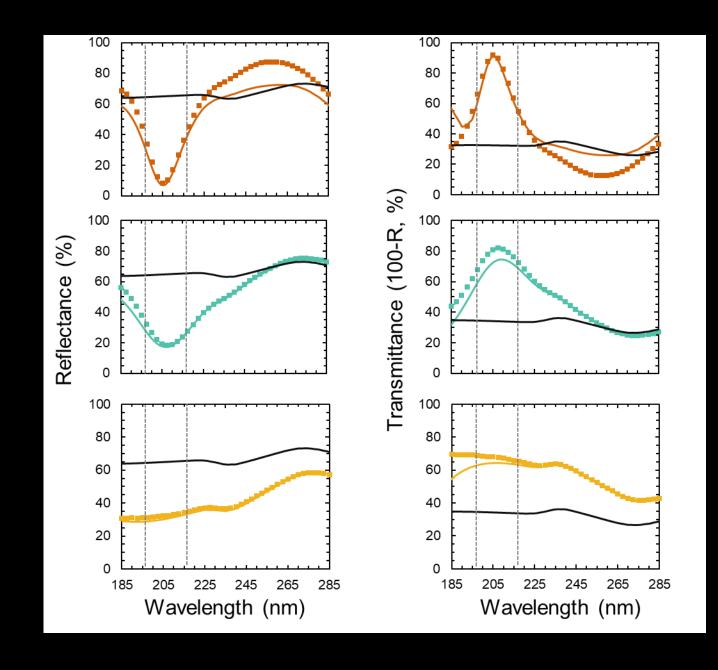




PI – C. Martin, Caltech @FIREBall2_scope

Kyne et al., JATIS, (2020) 011007

FIREBall-2 Multilayer AR Coatings



ALD Al₂O₃ ALD SiO ALD Al₂O₂ ALD SiO ALD Al₂O **Substrate** Five Layer AR Coating

ALD Al₂O₃ ALD SiO ALD Al₂O₂ **Substrate** Three Layer AR Coating

ALD Al₂O₃ **Substrate** Single Layer AR Coating

Layer thicknesses for these coatings are 17-40 nm



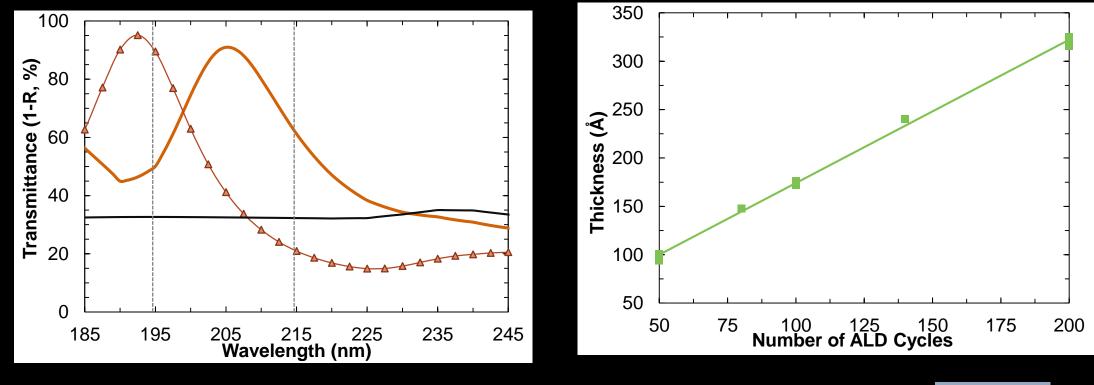




ALD Stacks & Film Nucleation

Growth based on initial calibration

ALD SiO₂ growth rate calibration



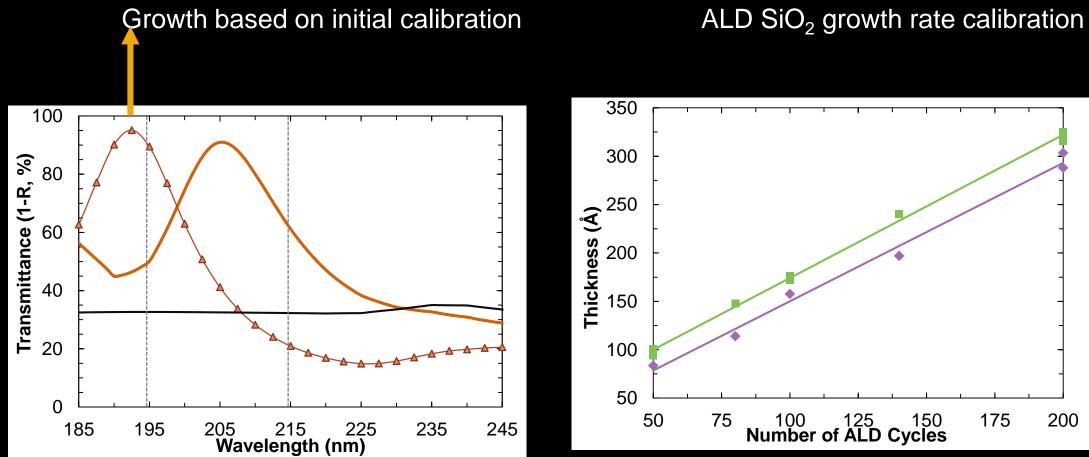


Five Layer AR Coating

Jewell, et al., Proc. SPIE 9601 (2015)

April Jewell, SCCAVS Lecture

ALD Stacks & Film Nucleation

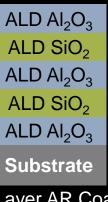


ALD SiO₂ nucleation on an existing ALD-Al₂O₃ layer is slower than on the bare substrate.

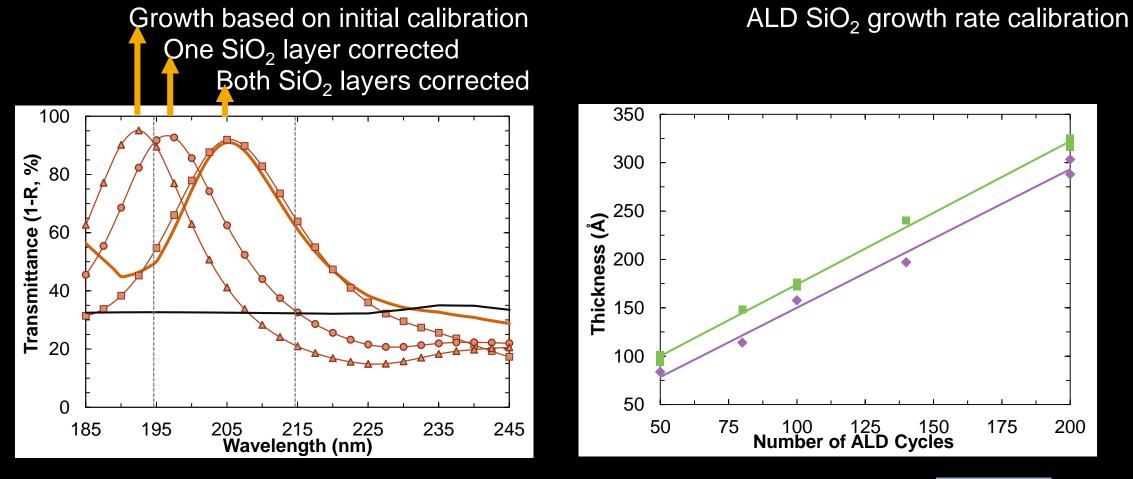
Five Layer AR Coating

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ALD Stacks & Film Nucleation

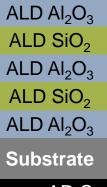


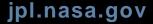
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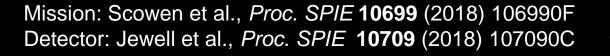


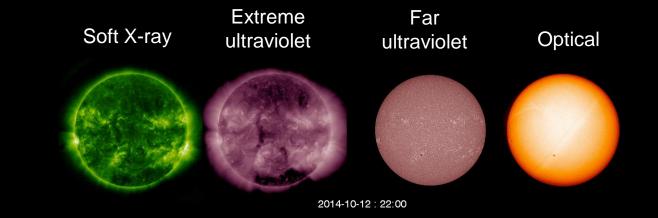


Current CubeSat Mission – SPARCS

Star-Planet Activity Research CubeSat

- M dwarf (or "red dwarf") stars in our galaxy host roughly 40 billion terrestrial planets in the habitable zone
- The stellar UV emission from M dwarfs is strong and highly variable, and impacts planetary atmospheric loss, composition, and habitability
- M dwarfs are much more active than the sun, but long term UV monitoring has not been done for M dwarfs.
- We want to know how active they are across the UV range and across planet formation and evolution timescales





April Jewell, SCCAVS Lecture

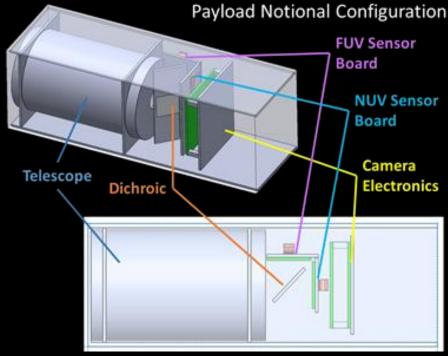
PI – E. Shkolnik, University of Arizona https://sparcs.asu.edu/

NASA/SDO/J. Llama https://sparcs.asu.edu/

SPARCS Payload

9-cm aperture telescope Dichroic element Transition at $\lambda \approx 233$ nm **NUV Bandpass Filter** SPARCam: Two channel UV camera Band NUV: 260-300 nm Band FUV: 150-170 nm

Image courtesy N. Struebel AZ Space Technologies LLC



Mission: Scowen et al., Proc. SPIE 10699 (2018) 106990F Detector: Jewell et al., Proc. SPIE 10709 (2018) 107090C

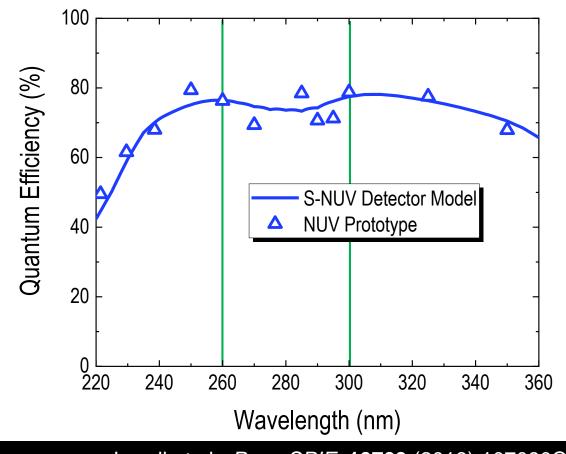
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PI – E. Shkolnik, University of Arizona https://sparcs.asu.edu/



Delta-doped CCD with High UV QE

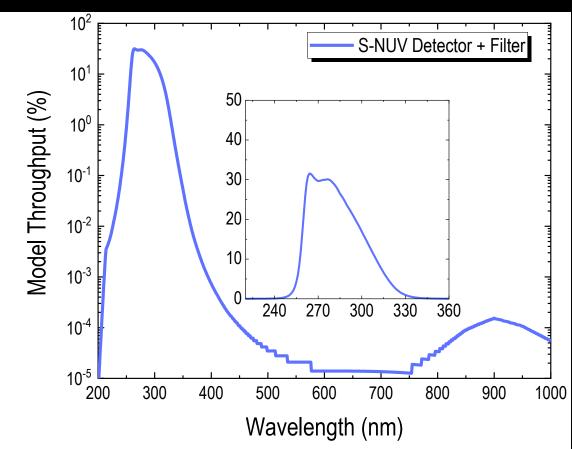
- JPL's doping processes yield nearly 100% internal QE
- Simple, single layer HfO₂ AR coating used to improve in-band response
- The SPARCS NUV prototype detector exhibits >70% QE throughout the S-NUV band



Jewell et al., Proc. SPIE 10709 (2018) 107090C

Red Leak Suppression

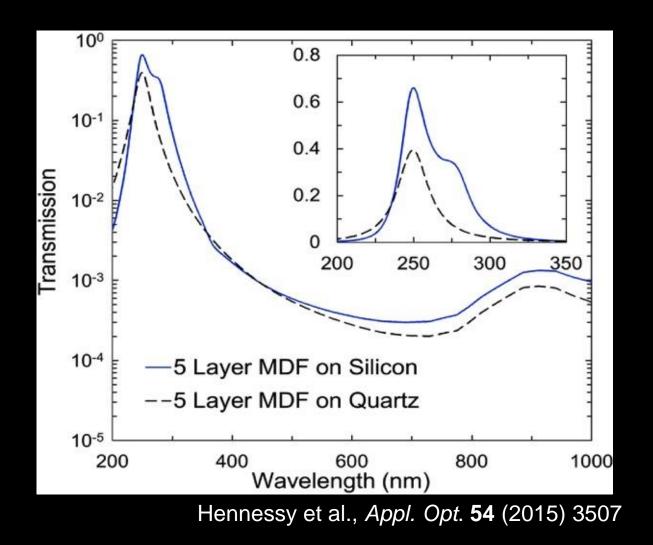
- SPARCS will use bandpass filters to minimize red leak
- We will use a commercial bandpass filter in the NUV channel
- Defines bandpass and central wavelength
- Results in throughput of ~30% in NUV channel
- Provides ≥OD3 to 1000 nm



Jewell et al., Proc. SPIE 10709 (2018) 107090C

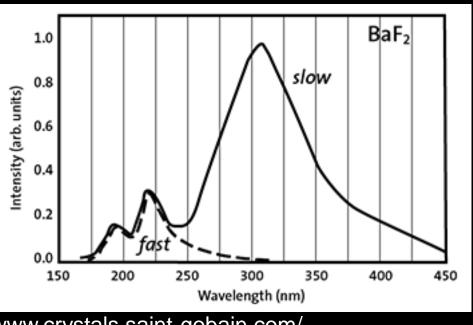
Solar-blind Silicon

- No commercial filter available meets SPARCS' needs
- JPL has developed solar-blind filters for silicon detectors
 - Metal-dielectric filter (MDF) stack (i.e., Fabry-Perot structure) deposited directly on silicon substrate
 - Allows for index matching
 - Can match dielectric to suit our needs

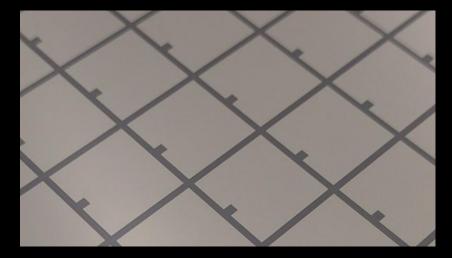


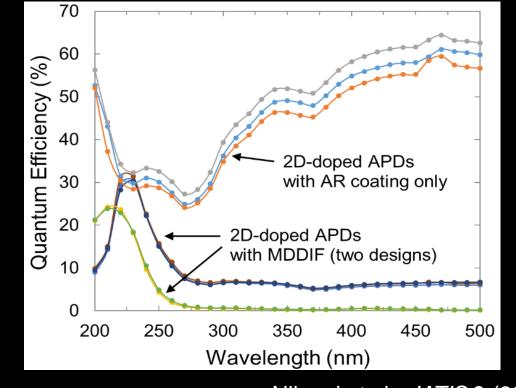
Solar-blind Silicon for Physics Applications

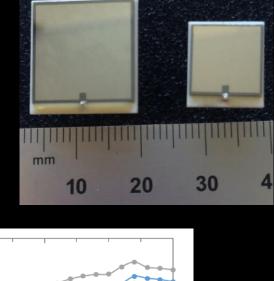
- Previously developed for use with Si avalanche photodiodes (APDs) for fast scintillation detection with BaF₂
 - Filter made with Al/Al₂O₃ stack
 - $\lambda_o = 220 \text{ nm} (\Delta \lambda = 20 \text{ nm FWHM})$



www.crystals.saint-gobain.com/



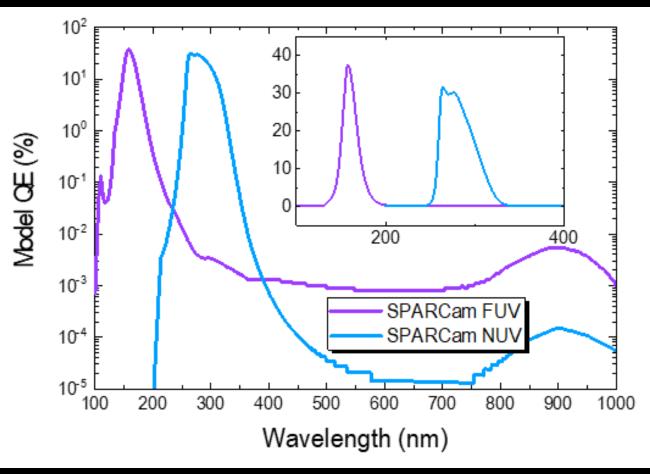




Nikzad et al., JATIS 3 (2017) 3507

Optimized Solar-blind FUV Detector

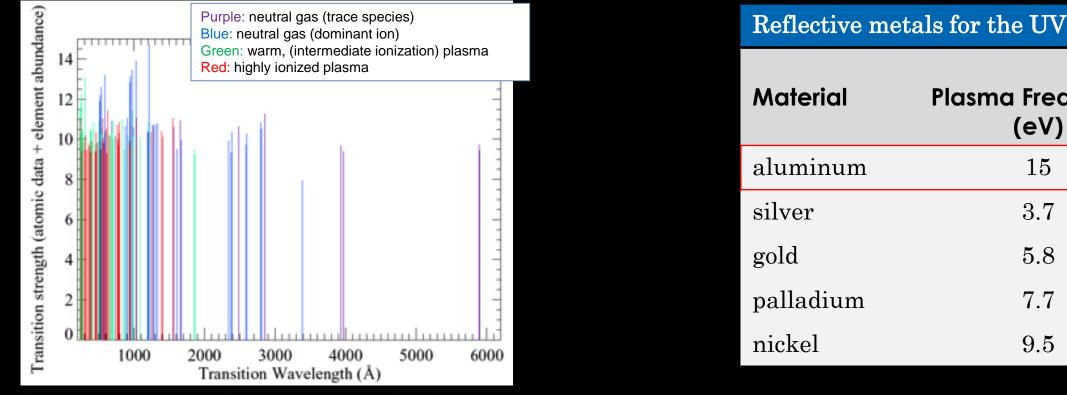
- MDF design will be optimized for **SPARCS**
- Filter is based on Al/AIF₃ where the ightarrowthickest layer is <40 nm



Jewell et al., Proc. SPIE 10709 (2018) 107090C

Thin Film Coatings for Reflective Optics

Materials challenges in the far ultraviolet

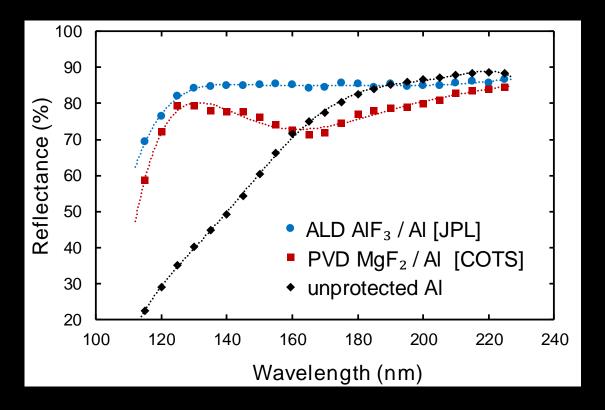


[Scowen, P.A., et al., Proc. SPIE 10398, 1039807 (2017)]

- Earth's atmosphere is opaque below 320 nm
- The high density of diagnostic lines in the FUV motivates interest for astrophysics
- The free-electron behavior of AI makes it highly reflective in the UV, but also very reactive and its oxide is strongly absorbing in the UV
 - \rightarrow 90-115 nm is an interesting part of the spectrum but the same physics make high throughput challenging

Plasma Frequency (eV) 15 3.75.87.79.5

Protecting AI Mirrors with Metal Fluoride Materials



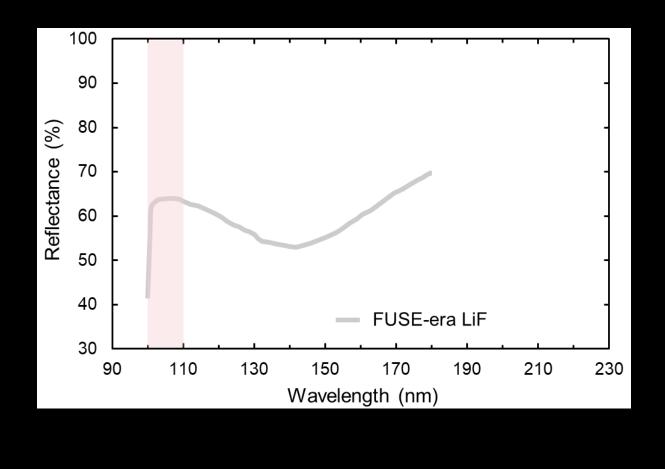
<u>Material</u>	Co-reactant with Anhydrous HF	<u>T_{substrate} (°C)</u>	<u>~λ Cutoff (nm)</u>
MgF_2	bis(ethylcyclopentadienyl) magnesium	100-250	115-120
AIF_3	trimethylaluminum	100-200	105-110
LiF	lithium bis(trimethylsilyl)amide	100-250	95-100

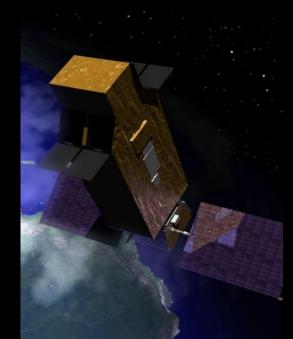
- Utilize anhydrous HF as the fluorine-containing precursor
- Large dependence on temperature for all processes
- Can deposit all materials at 100 °C

[Hennessy, J., et al., JVST A 33, 01A125 (2015)]
[Hennessy, J., et al., JVST A 34, 01A120 (2016)]
[Hennessy, J., et al., Inorganics 6, 46 (2018)]

-containing precursor or all processes

LiF as a mirror coating material



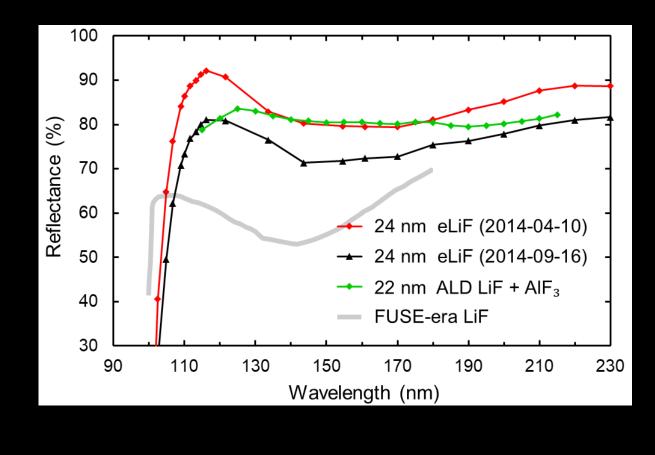


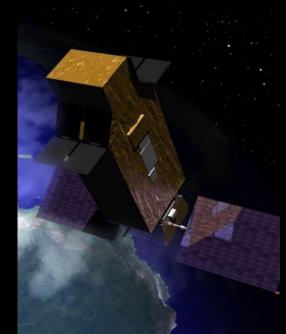
FUSE Launched 1999 ~0.4 m Mirror/Channel 15 nm of LiF on Al λ_{min}^* ~ 100 nm

- Far ultraviolet spectroscopic explorer (FUSE) used LiF-protected AI to operate 100–110 nm bandpass
- Overall reflectance was moderate, entire instrument was 'bagged' and purged with nitrogen during assembly, integration, and testing

D–110 nm bandpass n nitrogen during

LiF as a mirror coating material





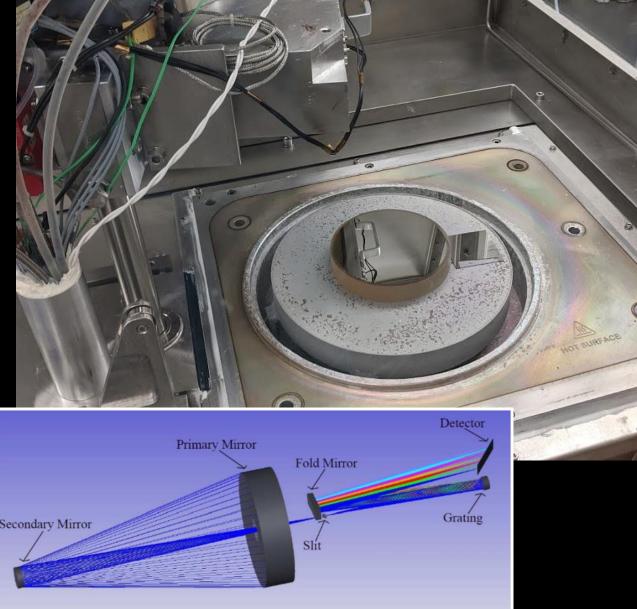
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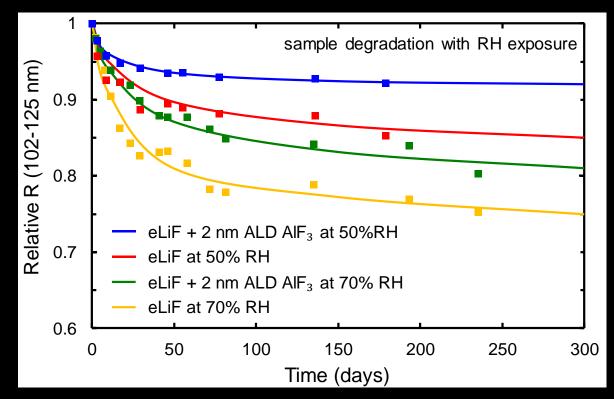
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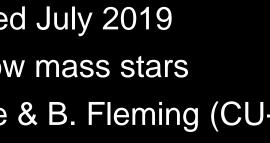
Encapsulating the Protective Layer

100 mm convex SISTINE secondary overcoated at JPL





- Coating LiF with another ultrathin (<2 nm) fluoride can enhance stability
- SISTINE sounding rocket launched July 2019
 - Look at UV radiation from low mass stars ullet
 - Collaboration with K. France & B. Fleming (CUullet**Boulder**)



Team and Collaborators

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